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Executive Summary

EXECUTIVE SUMMARY

Device: IBM Miami (ibm_miami)
Topology: Heavy-hex lattice
Total Qubits: 120
Operational Qubits: 120
Total CZ Edges: 216

CONNECTIVITY

Interior qubits (4 neighbors): 77
Edge qubits (3 neighbors): 38
Corner qubits (2 neighbors): 5

COHERENCE TIMES

T1: 312.3 +/- 111.6 us (range: 16.0 - 567.7 us)
T2: 271.2 +/- 98.1 us (range: 34.4 - 574.2 us)
T2/T1 ratio: 0.87 (ideal limit: 2.0)

GATE ERRORS

Single-qubit (ID): 0.030% mean (0.022% median)
Two-qubit (CZ): 0.70% mean (0.29% median)
CZ gate length: 164 +/- 68 ns

READOUT

Assignment error: 2.41% mean
P(0|1) [false negative]: 3.28%
P(1|0) [false positive]: 1.68%

KEY OBSERVATIONS

- CZ error distribution is highly right-skewed (mean >> median)
- 29 CZ edges are outliers (>0.007)
- Worst CZ error: 17.3% (qubits 6-7)
- 3 qubits violate $T2 \leq 2 \cdot T1$ physical limit (measurement artifact or pulse errors)

Device Overview

IBM Miami is a 120-qubit superconducting quantum processor based on IBM's heavy-hex lattice topology. Each qubit is a transmon - an anharmonic oscillator formed by a Josephson junction shunted by a capacitor. The device operates at millikelvin temperatures (~ 15 mK) in a dilution refrigerator to minimize thermal excitations.

The heavy-hex topology arranges qubits in a pattern where most interior qubits have 4 nearest neighbors, while boundary qubits have 2-3 neighbors. This geometry is optimized for error correction codes while maintaining high-fidelity two-qubit gates.

Parameter Definitions (1/6)

****Qubit Index****

Integer identifier (0-119) for each physical qubit on the chip. The numbering follows the chip's spatial layout in the heavy-hex lattice topology.

****T1 Relaxation Time (Energy Decay)****

T1 characterizes the timescale for energy relaxation from the excited state $|1\rangle$ to the ground state $|0\rangle$. This is analogous to the longitudinal relaxation time in NMR.

Physical mechanism: The qubit couples to its electromagnetic environment (substrate defects, quasiparticles, radiation), causing spontaneous emission. The decay follows:

$$P_1(t) = P_1(0) \times \exp(-t/T1)$$

Longer T1 allows more gate operations before decoherence. Values $>300 \mu\text{s}$ are considered excellent for superconducting qubits. Low T1 often indicates material defects or spurious coupling to lossy modes.

****T2 Dephasing Time (Phase Coherence)****

T2 characterizes the timescale for loss of phase coherence in a superposition state.

For a state $|\psi\rangle = (|0\rangle + |1\rangle)/\sqrt{2}$, the off-diagonal density matrix elements decay as $\exp(-t/T2)$.

Physical mechanisms:

- T1 processes (energy decay also causes dephasing)
- Pure dephasing from low-frequency noise (flux noise, charge noise)

Fundamental limit: $T2 \leq 2 \times T1$ (from Bloch equations). T2 approaching $2 \times T1$ indicates T1-limited dephasing with minimal pure dephasing - a sign of a well-isolated qubit.

T2 is typically measured via Ramsey or Hahn echo sequences. Values reported here are likely $T2^*$ (Ramsey) or T2 echo, depending on IBM's calibration protocol.

Parameter Definitions (2/6)

****Readout Assignment Error****

The probability of incorrectly assigning the qubit state after measurement. This is the average of the two types of misclassification:

$$\epsilon_{\text{readout}} = (P(0|1) + P(1|0)) / 2$$

Modern superconducting qubit readout uses dispersive measurement: the qubit state shifts the resonant frequency of a coupled readout resonator. A microwave pulse probes this resonator, and the reflected/transmitted signal is amplified and digitized.

Errors arise from:

- Finite signal-to-noise ratio in the measurement chain
- T1 decay during measurement (state flip before readout completes)
- Readout resonator thermal population
- Imperfect state discrimination thresholds

****P(0|1) - False Negative Rate****

Probability of measuring $|0\rangle$ when the qubit was prepared in $|1\rangle$. This is primarily caused by T1 decay during the measurement process.

If the readout duration is τ_{read} and T1 is the relaxation time:

$$P(0|1) \approx 1 - \exp(-\tau_{\text{read}} / T1)$$

High $P(0|1)$ often correlates with low T1 or long readout pulses.

****P(1|0) - False Positive Rate****

Probability of measuring $|1\rangle$ when the qubit was prepared in $|0\rangle$. This can arise from:

- Thermal excitation of the qubit
- Measurement-induced excitation (QND violation)
- Readout resonator thermal population creating spurious signals
- Discrimination threshold errors

This error is typically smaller than $P(0|1)$ since there's no T1 decay channel from $|0\rangle$ to $|1\rangle$ at millikelvin temperatures.

Parameter Definitions (3/6)

****Readout Pulse Duration****

The duration of the microwave pulse used to probe the readout resonator. Longer pulses provide better signal-to-noise (more photons) but increase the window for T1 decay.

Typical values: 500-3000 ns. The optimal length balances SNR against T1 decay. IBM Miami uses 2400 ns uniformly across all qubits.

****Identity Gate Error****

Error rate of the identity (idle) operation over one gate cycle. This benchmarks decoherence during the time a qubit waits while other qubits are being operated on.

Measured via randomized benchmarking (RB) or similar protocols. The identity gate error sets a floor for all single-qubit operations since any gate includes at least this much decoherence.

ID error $\approx (\text{gate_time} / T1 + \text{gate_time} / T2) / 2$ for ideal gates.

****Single-Qubit Gate Duration****

Time to execute a single-qubit gate (e.g., X, Y, \sqrt{X}). For transmon qubits, these are microwave pulses at the qubit transition frequency.

Typical values: 20-50 ns. Shorter gates reduce decoherence during operations but require higher drive power (risking leakage to non-computational states).

IBM Miami uses 32 ns gates, which is relatively fast.

Parameter Definitions (4/6)

****RX Gate Error (X-rotation)****

Error rate for arbitrary rotations around the X-axis of the Bloch sphere. Measured via randomized benchmarking.

Physical implementation: A resonant microwave pulse with controlled amplitude and duration. Errors arise from:

- Pulse calibration imperfections (amplitude, frequency, phase)
- Decoherence during the gate
- Leakage to higher transmon levels
- Crosstalk from neighboring qubits

****RZ Gate Error (Z-rotation)****

Error rate for rotations around the Z-axis. In IBM's implementation, RZ gates are "virtual" - implemented by adjusting the phase of subsequent pulses rather than applying a physical pulse.

Virtual RZ gates have essentially zero error (only software phase tracking), which is why this column shows 0 for all qubits. This is a standard technique in superconducting qubit control.

****SX Gate Error (\sqrt{X} gate)****

Error rate for the square-root of X gate, which performs a $\pi/2$ rotation around X. This is one of IBM's native gate set elements (along with RZ and CZ/ECR).

SX followed by SX equals X. Using SX as a native gate allows efficient decomposition of arbitrary single-qubit rotations.

****X Gate Error (Bit Flip)****

Error rate for the Pauli-X gate (π rotation around X), equivalent to a classical NOT operation: $|0\rangle \leftrightarrow |1\rangle$.

Typically $X = SX \times SX$, so X error $\approx 2 \times$ SX error (approximately, neglecting correlations).

Parameter Definitions (5/6)

****CZ (Controlled-Z) Gate Error****

Error rate for the two-qubit controlled-Z gate between connected qubit pairs. CZ applies a π phase to the $|11\rangle$ state: $CZ|11\rangle = -|11\rangle$.

Format: "neighbor1:error1;neighbor2:error2;..." listing all connected qubits and their respective CZ error rates.

Physical implementation varies (cross-resonance, tunable coupler, etc.). Two-qubit gates are typically 10-100× noisier than single-qubit gates due to:

- Longer gate duration
- Coupling to additional decoherence channels
- Calibration sensitivity
- Crosstalk and spectator qubit errors

CZ errors are the dominant error source in most quantum algorithms.

****CZ Gate Duration****

Duration of the two-qubit CZ gate for each qubit pair.

Format mirrors CZ error: "neighbor1:duration1;neighbor2:duration2;..."

Typical values: 100-500 ns. Duration varies by qubit pair due to:

- Frequency detuning between qubits
- Coupling strength
- Required pulse shaping for leakage suppression

Longer gates generally have higher error rates due to increased decoherence.

Parameter Definitions (6/6)

****Measurement Error****

Error rate for the measurement operation, typically equal to the readout assignment error. May include additional systematic effects from the measurement protocol.

Note: MEASURE error equals Readout assignment error in this dataset.

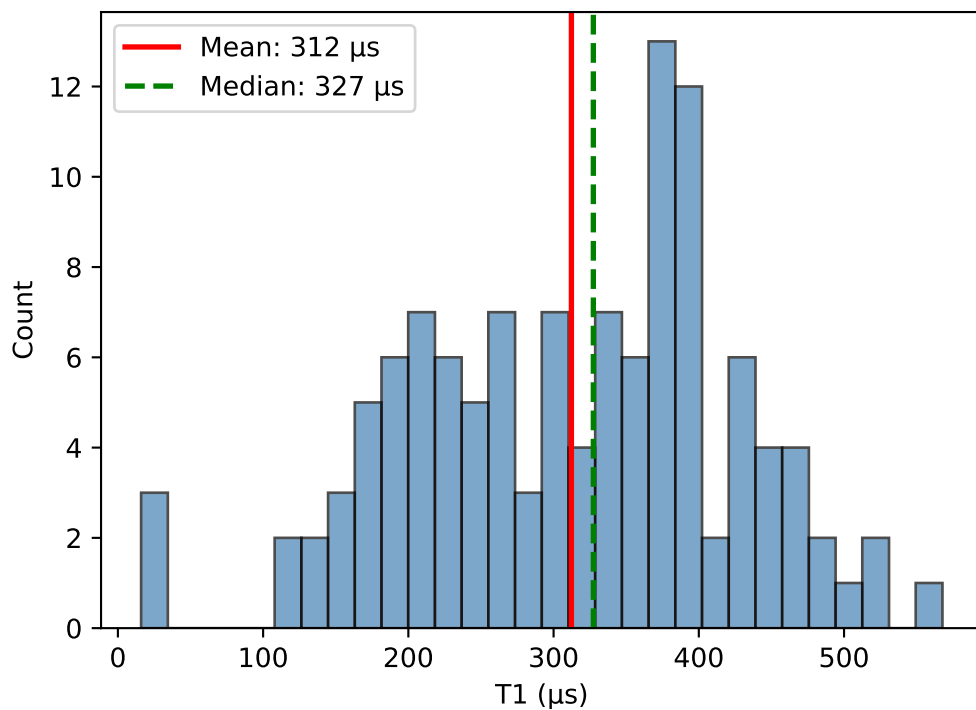
****Operational Status****

Whether the qubit passed calibration and is available for use. "Yes" indicates the qubit meets IBM's quality thresholds. Failed qubits would show "No" and should be avoided in circuit design.

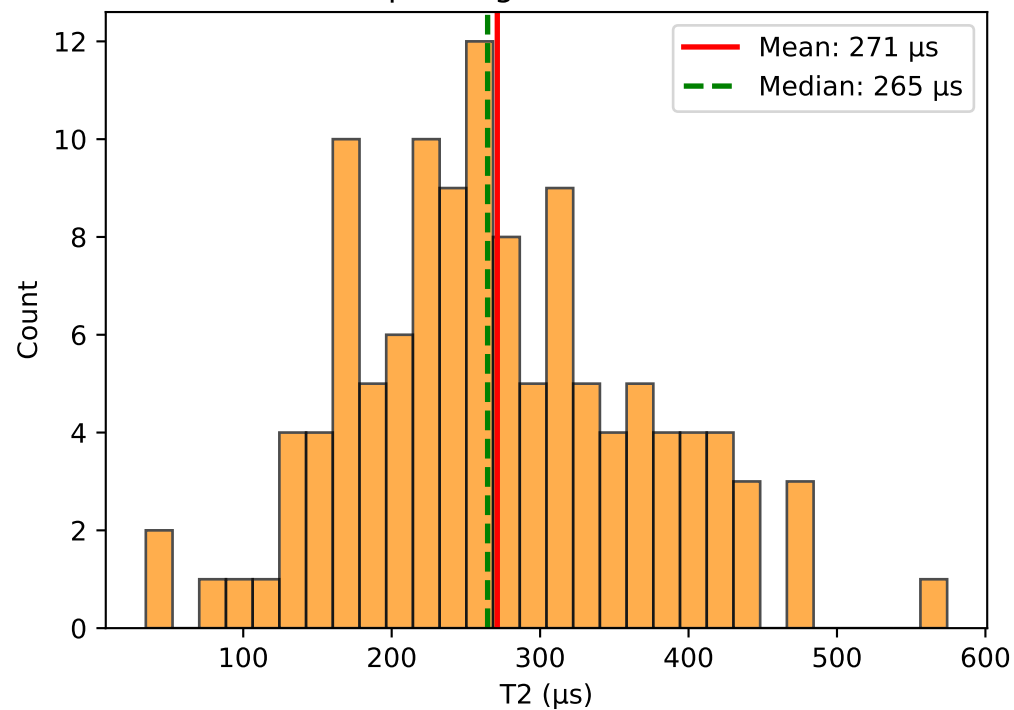
All 120 qubits are operational in this calibration snapshot.

Coherence Time Analysis (T1, T2)

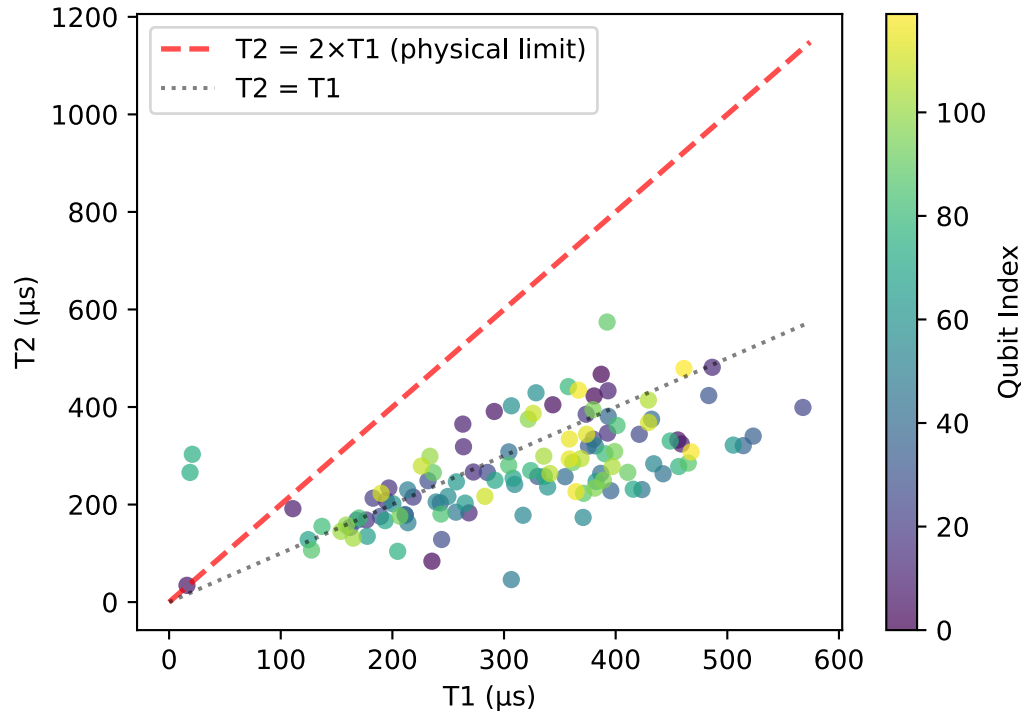
T1 Relaxation Time Distribution



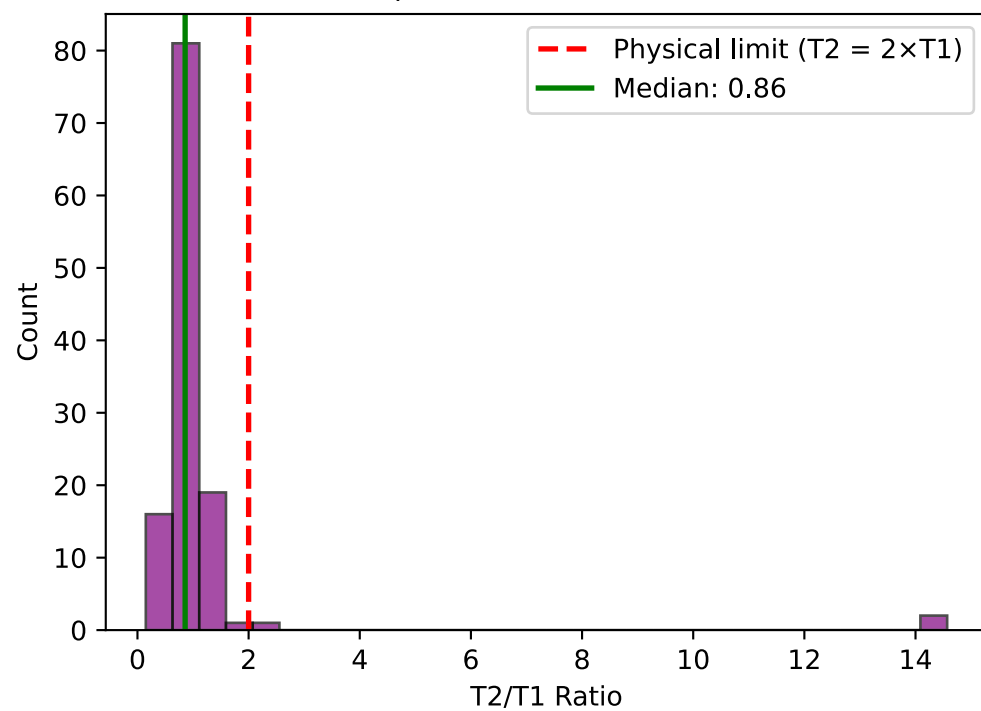
T2 Dephasing Time Distribution



T1 vs T2 Correlation

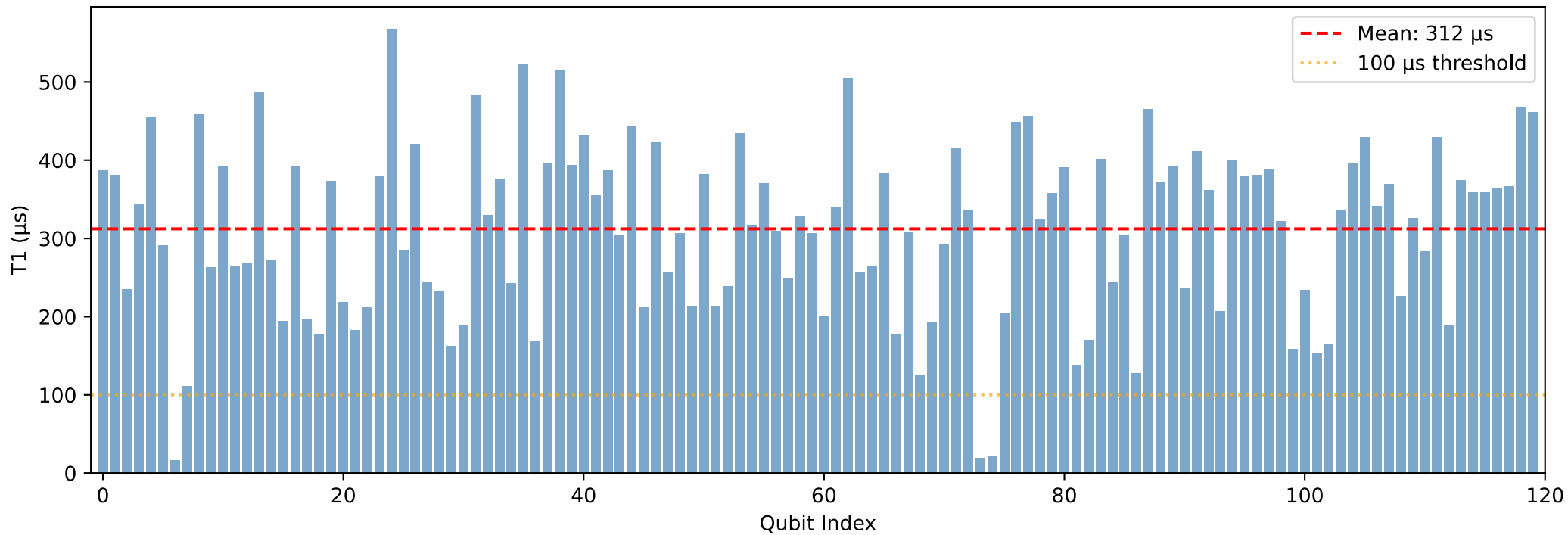


T2/T1 Ratio Distribution

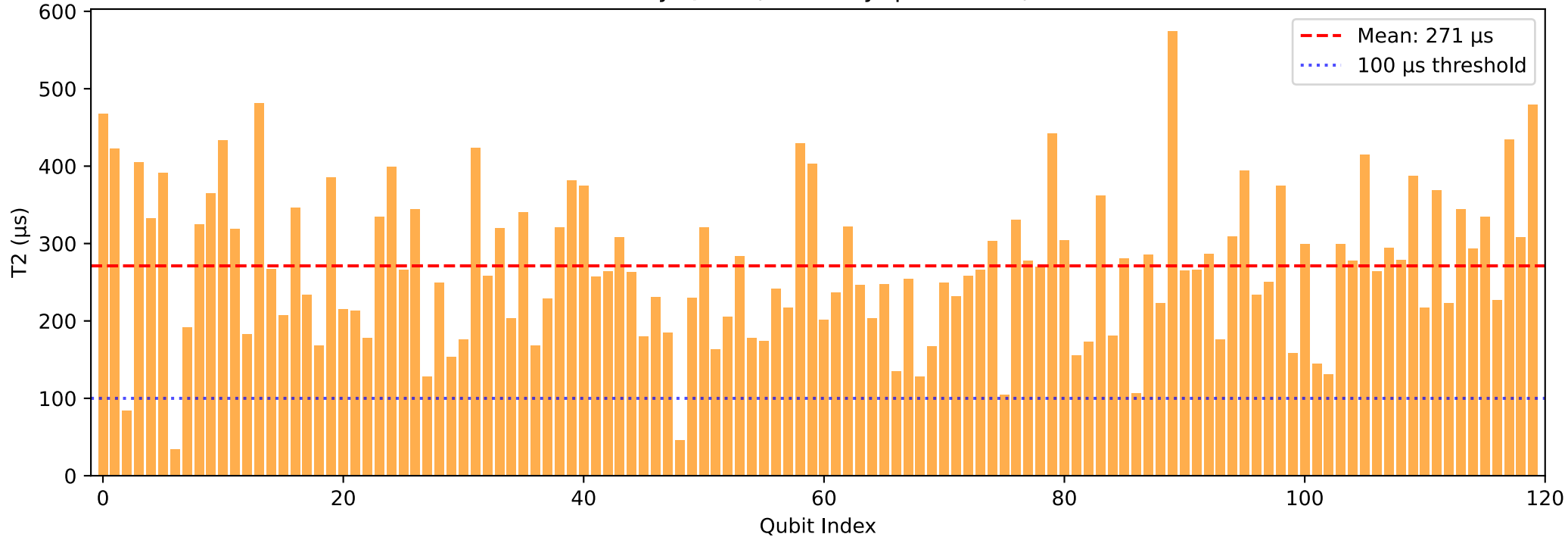


Coherence Times by Qubit

T1 by Qubit (sorted by qubit index)

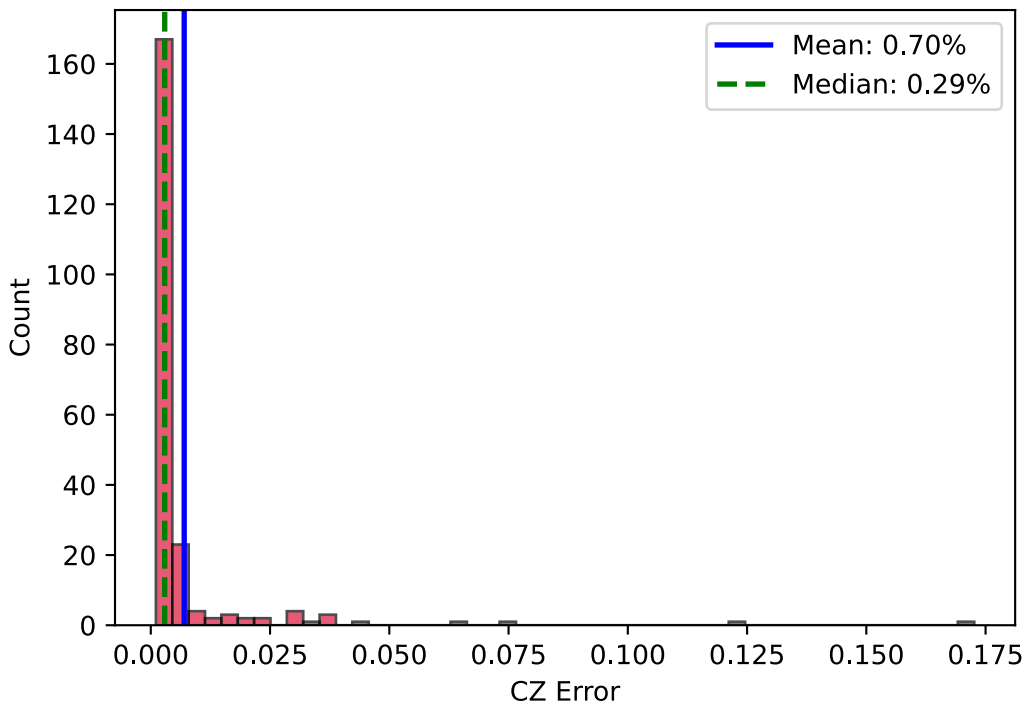


T2 by Qubit (sorted by qubit index)

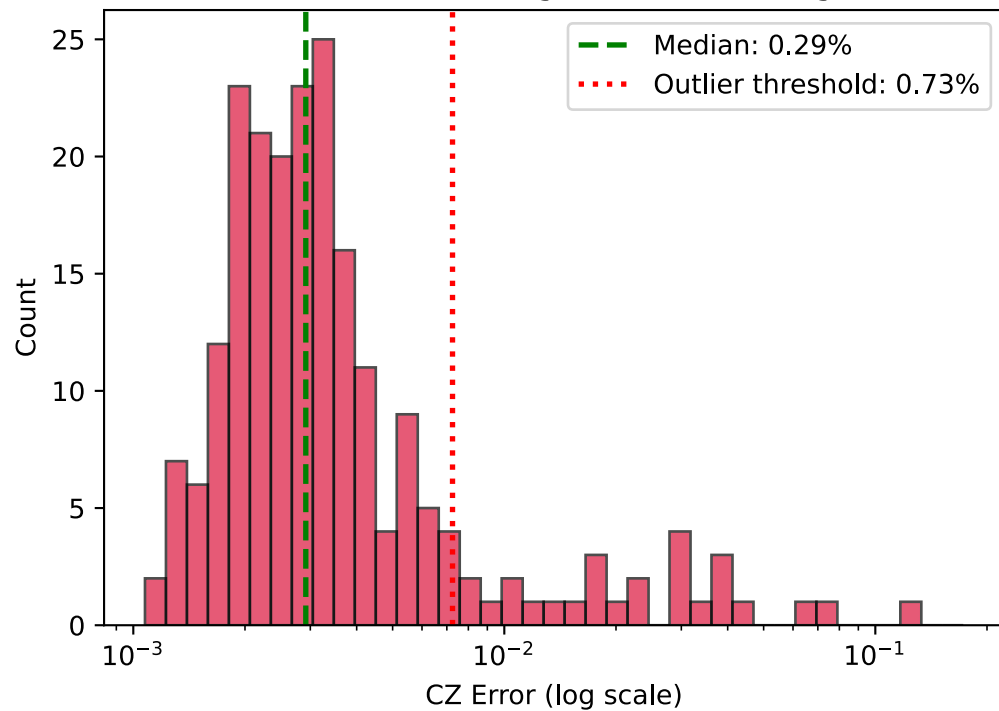


Two-Qubit (CZ) Gate Analysis

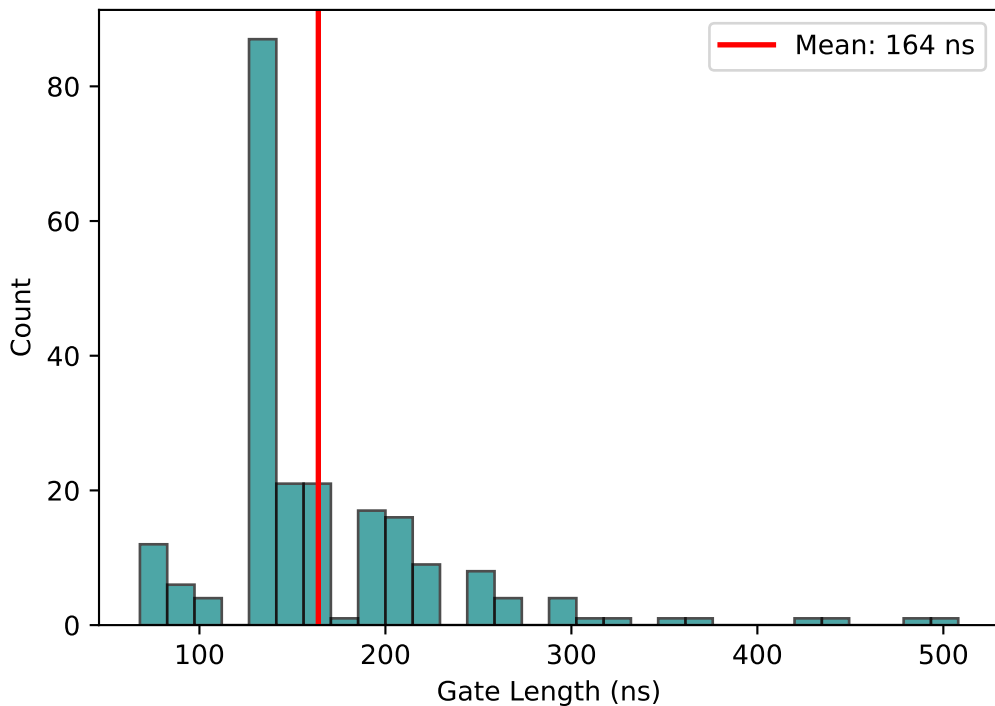
CZ Error Distribution (Linear Scale)



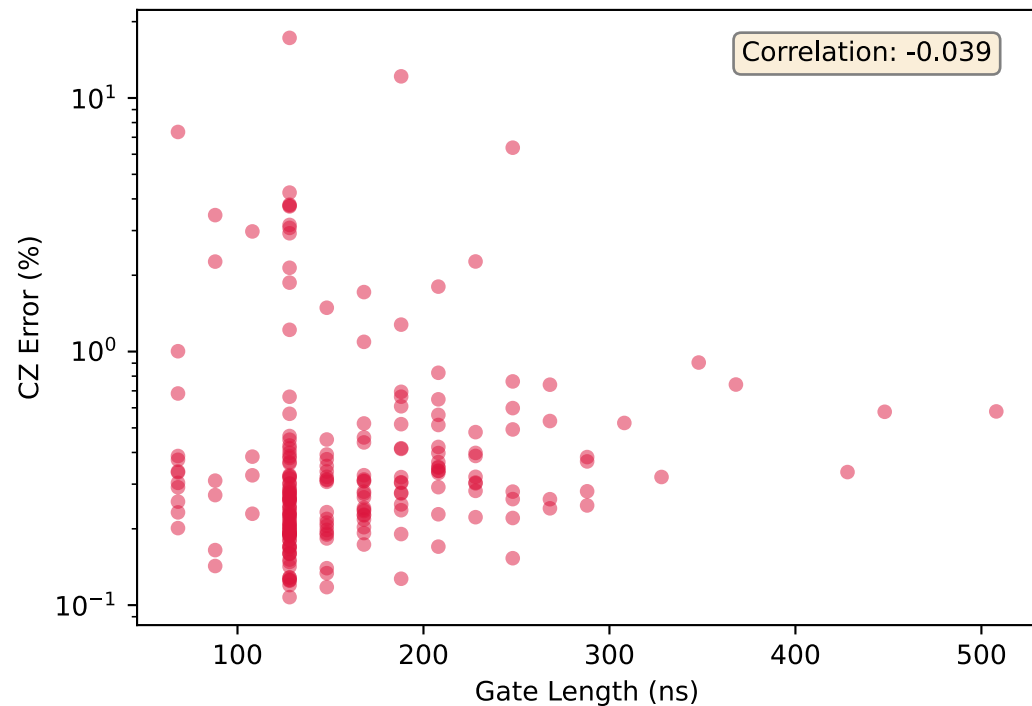
CZ Error Distribution (Log Scale) - Note Right Skew



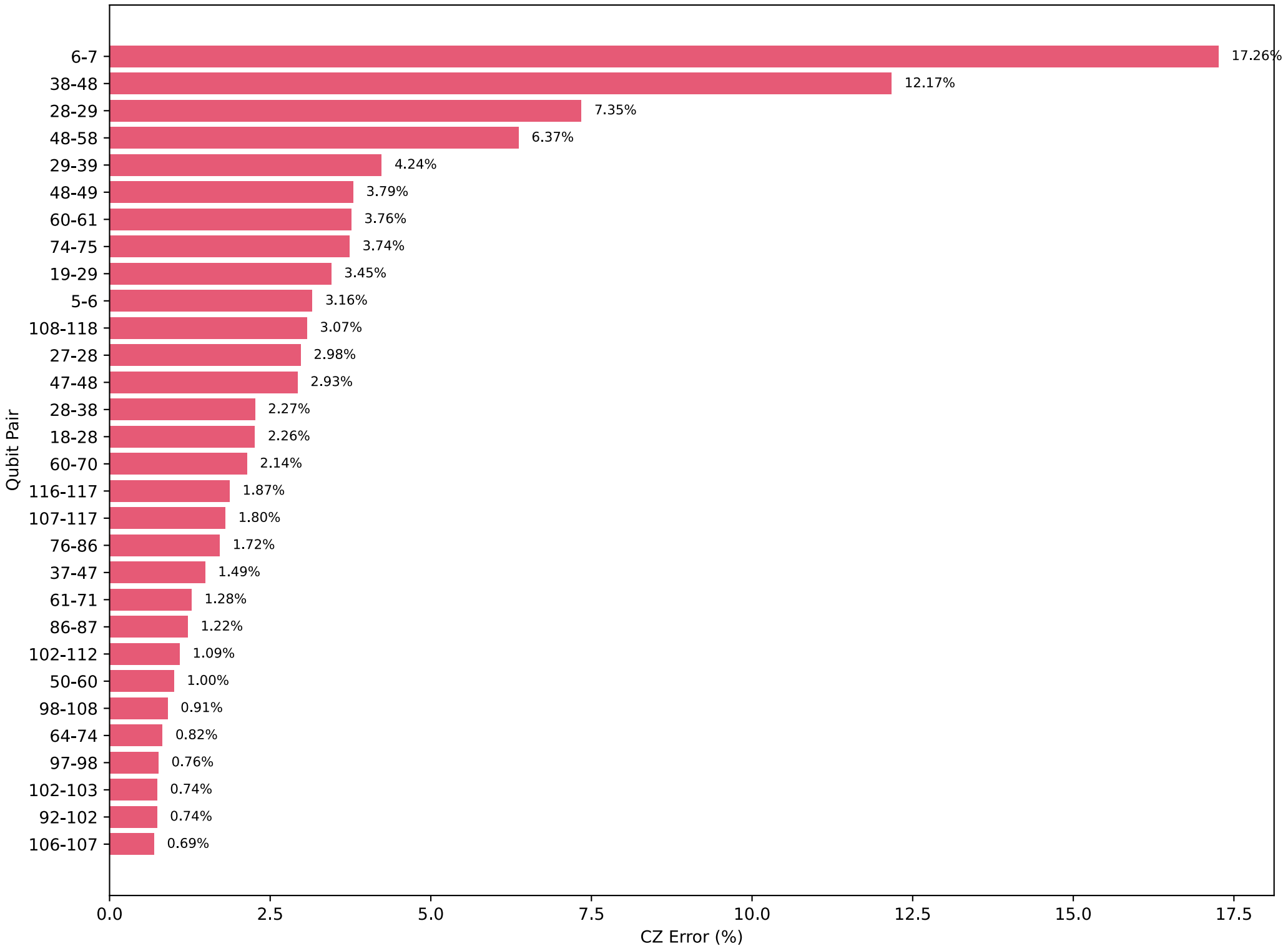
CZ Gate Duration Distribution



CZ Error vs Gate Duration

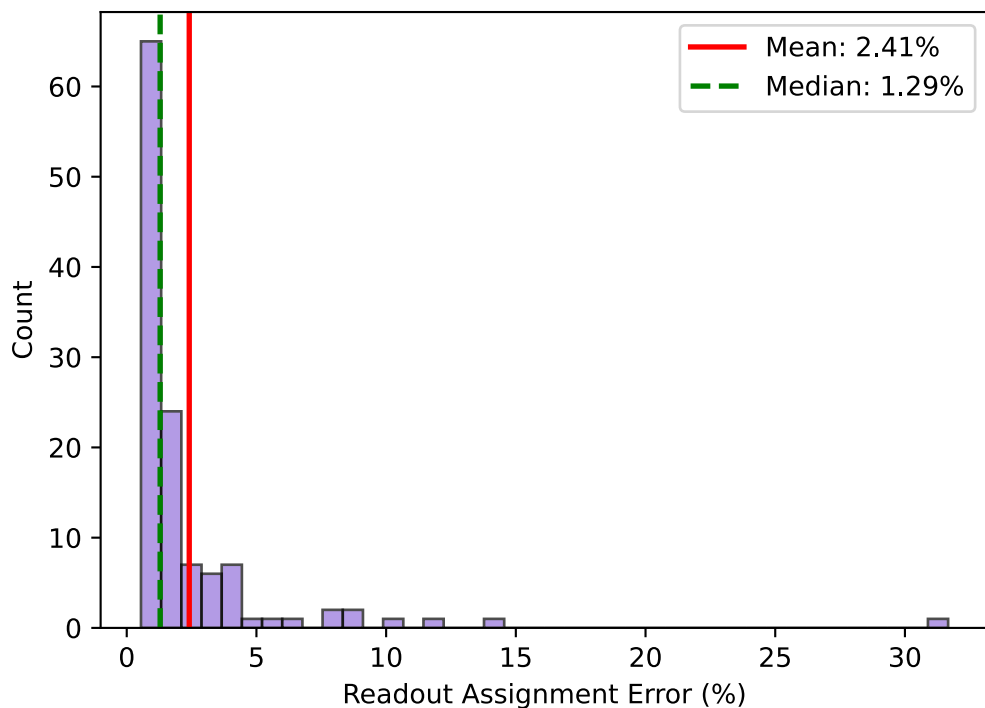


Worst CZ Gate Errors (Top 30)

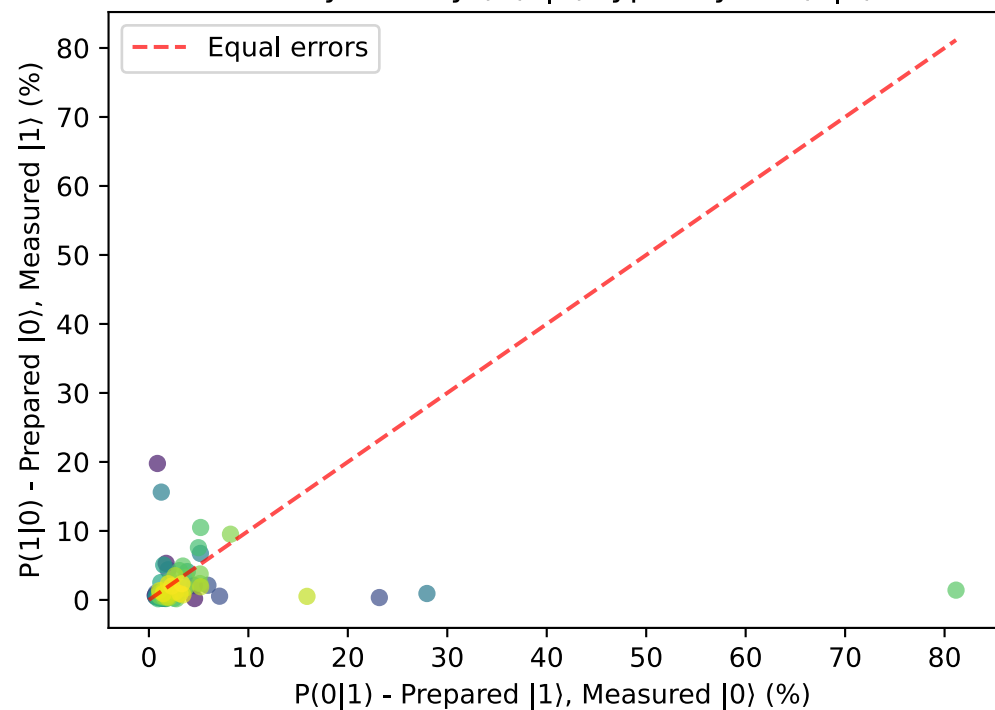


Readout/Measurement Error Analysis

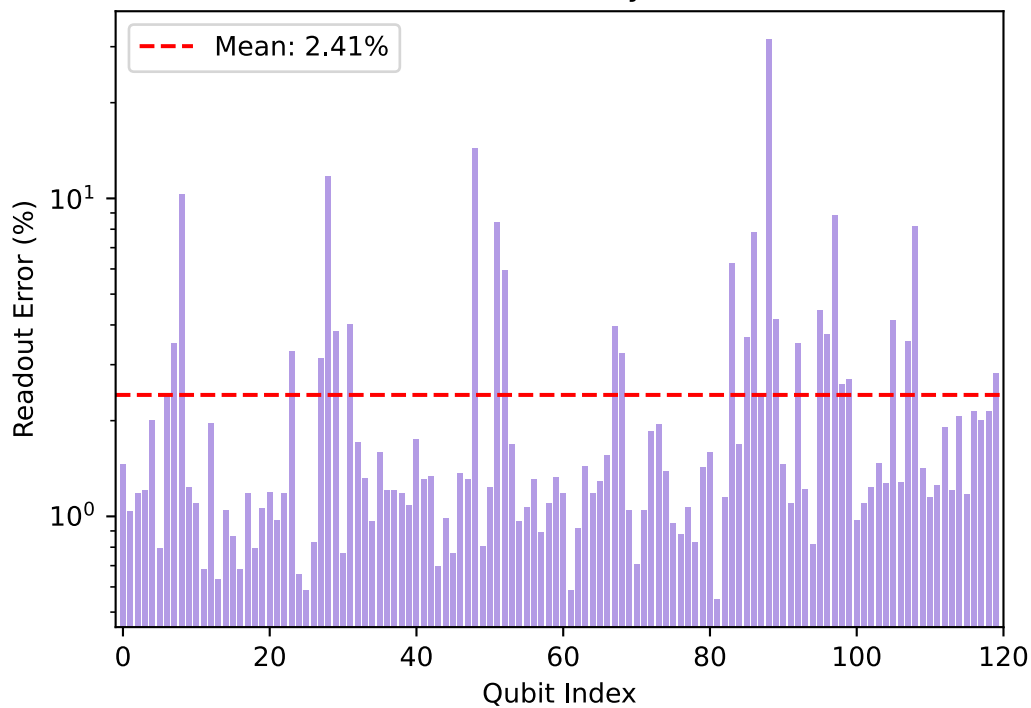
Readout Error Distribution



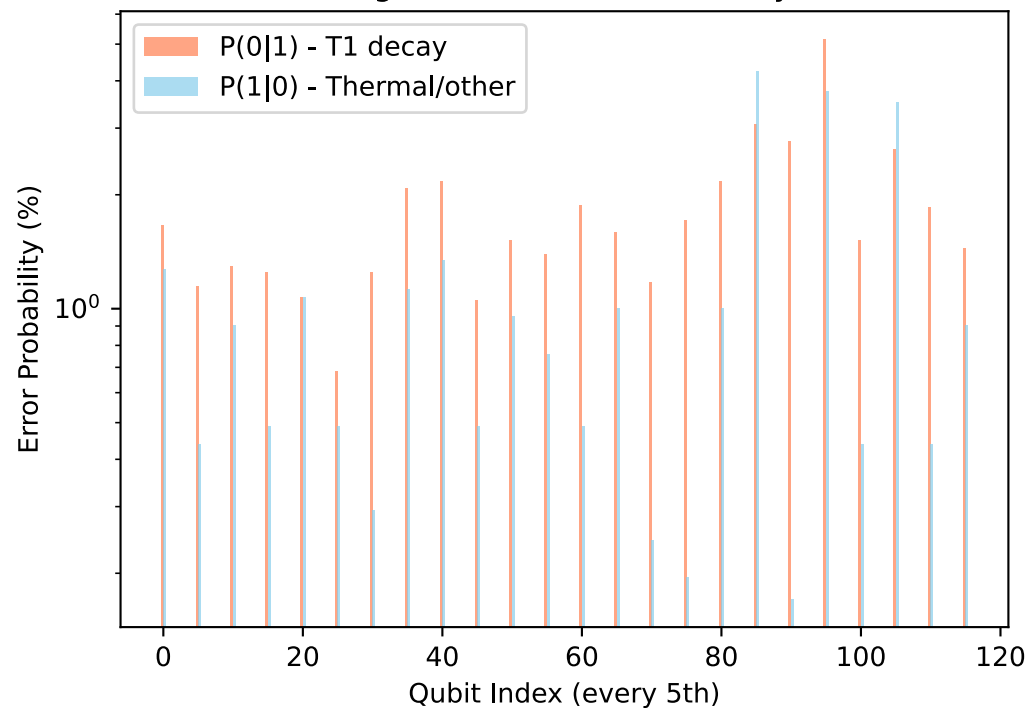
Readout Error Asymmetry ($P(0|1)$ typically $> P(1|0)$ due to T_1)



Readout Error by Qubit



False Negative vs False Positive by Qubit

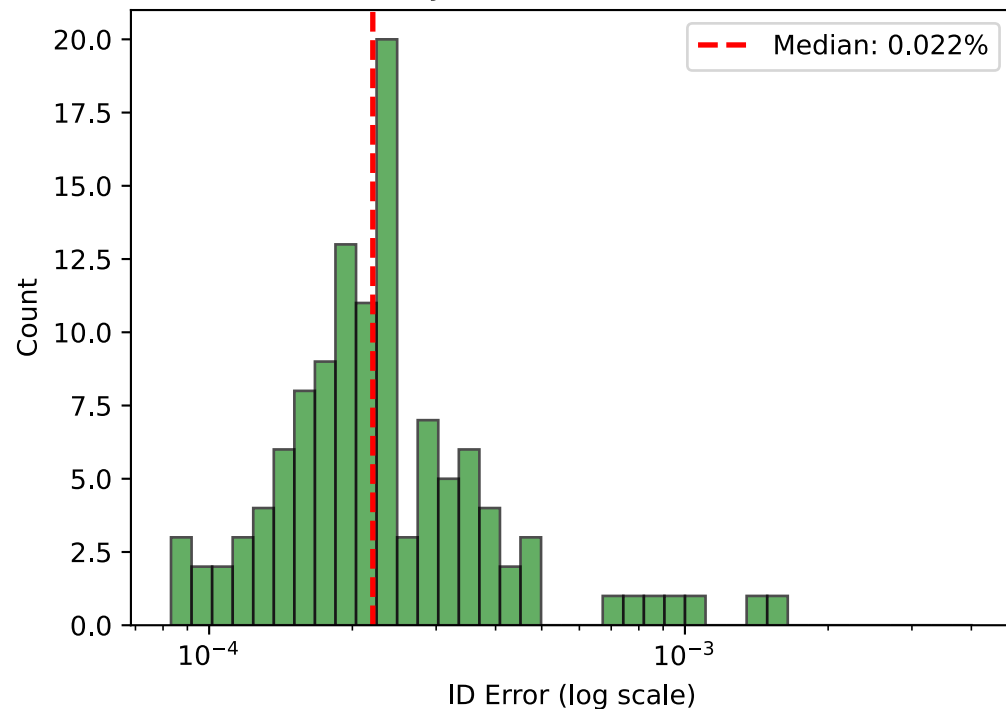


Top 20 Worst Readout Qubits
(Note correlation between high P(0|1) and T1)

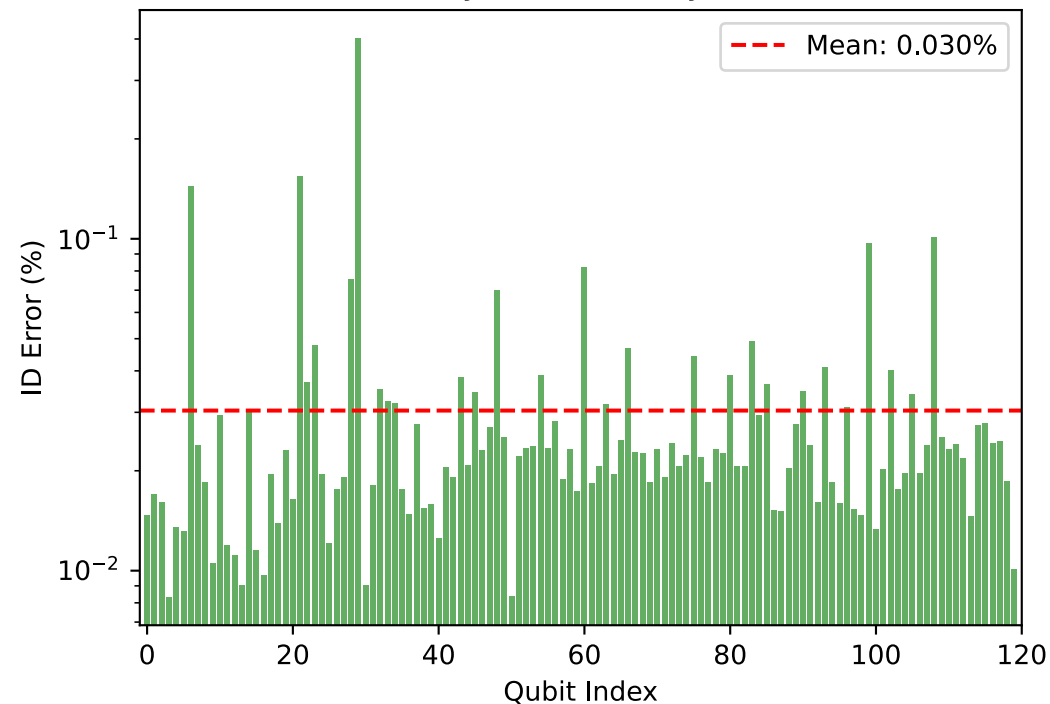
| Qubit | Assignment Error | P(0 1) | P(1 0) | T1 (μ s) |
|-------|------------------|--------|--------|---------------|
| 88 | 31.67% | 81.15% | 1.42% | 371.3 |
| 48 | 14.44% | 27.95% | 0.93% | 306.5 |
| 28 | 11.76% | 23.17% | 0.34% | 231.9 |
| 8 | 10.31% | 0.85% | 19.78% | 458.8 |
| 97 | 8.86% | 8.20% | 9.52% | 389.0 |
| 51 | 8.44% | 1.25% | 15.62% | 213.9 |
| 108 | 8.20% | 15.89% | 0.51% | 226.0 |
| 86 | 7.85% | 5.20% | 10.50% | 127.5 |
| 83 | 6.27% | 4.98% | 7.57% | 401.2 |
| 52 | 5.96% | 5.18% | 6.74% | 239.2 |
| 95 | 4.46% | 5.15% | 3.76% | 379.8 |
| 89 | 4.16% | 3.42% | 4.91% | 392.3 |
| 105 | 4.15% | 2.64% | 3.52% | 429.3 |
| 31 | 4.03% | 5.93% | 2.12% | 483.4 |
| 67 | 3.98% | 3.86% | 4.10% | 308.2 |
| 29 | 3.82% | 7.10% | 0.54% | 162.0 |
| 96 | 3.75% | 5.13% | 2.37% | 381.3 |
| 85 | 3.66% | 3.08% | 4.25% | 304.2 |
| 107 | 3.55% | 5.20% | 1.90% | 369.0 |
| 7 | 3.52% | 1.73% | 5.30% | 110.9 |

Single-Qubit Gate Error Analysis

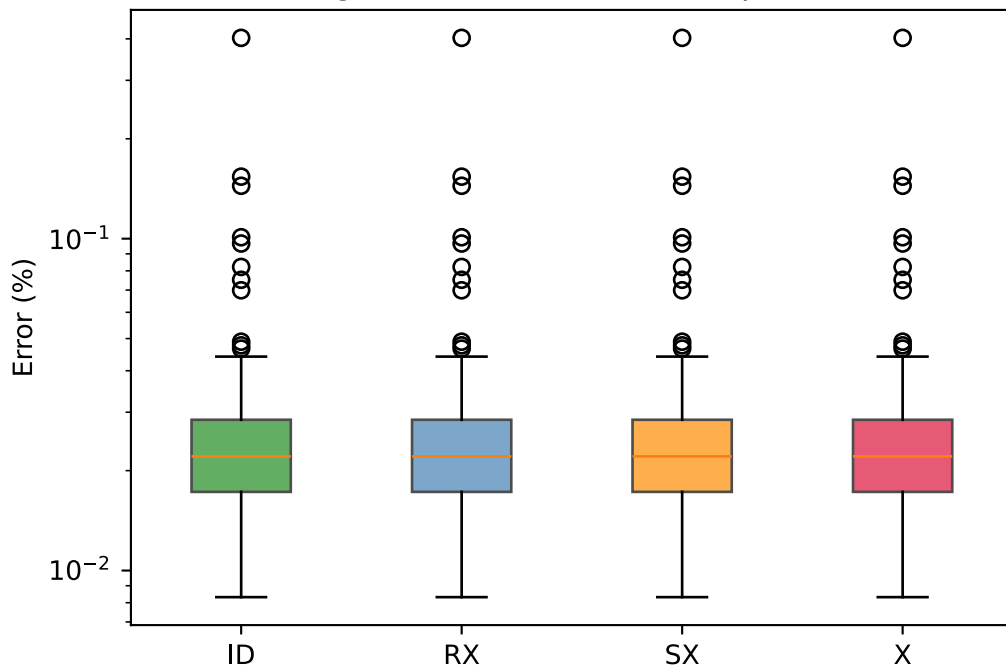
Identity Gate Error Distribution



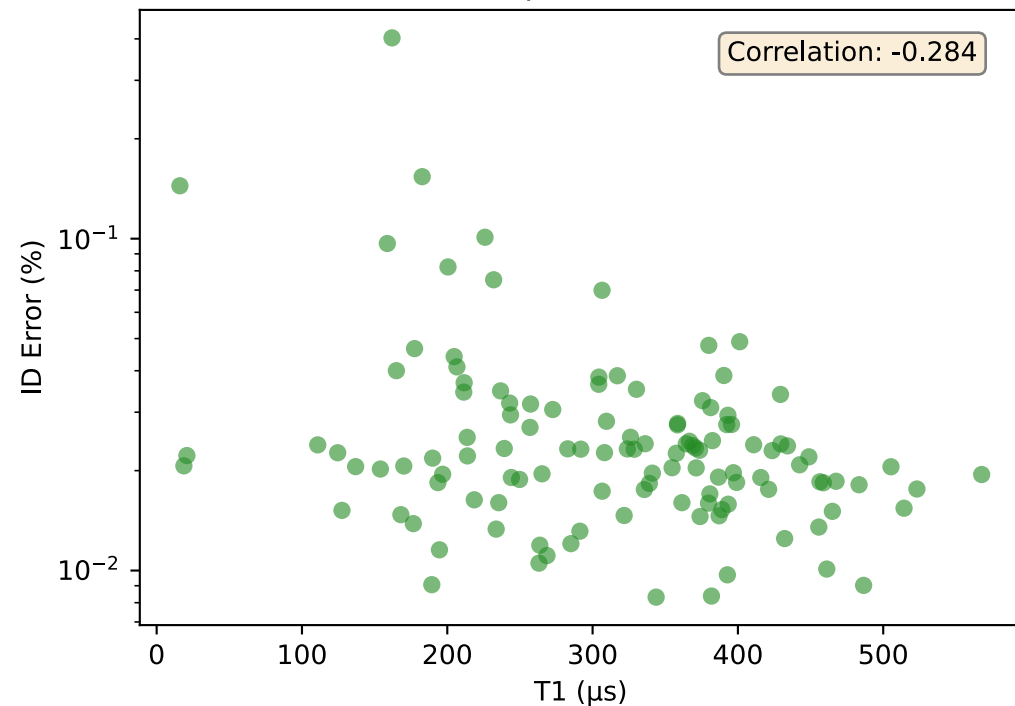
Identity Gate Error by Qubit



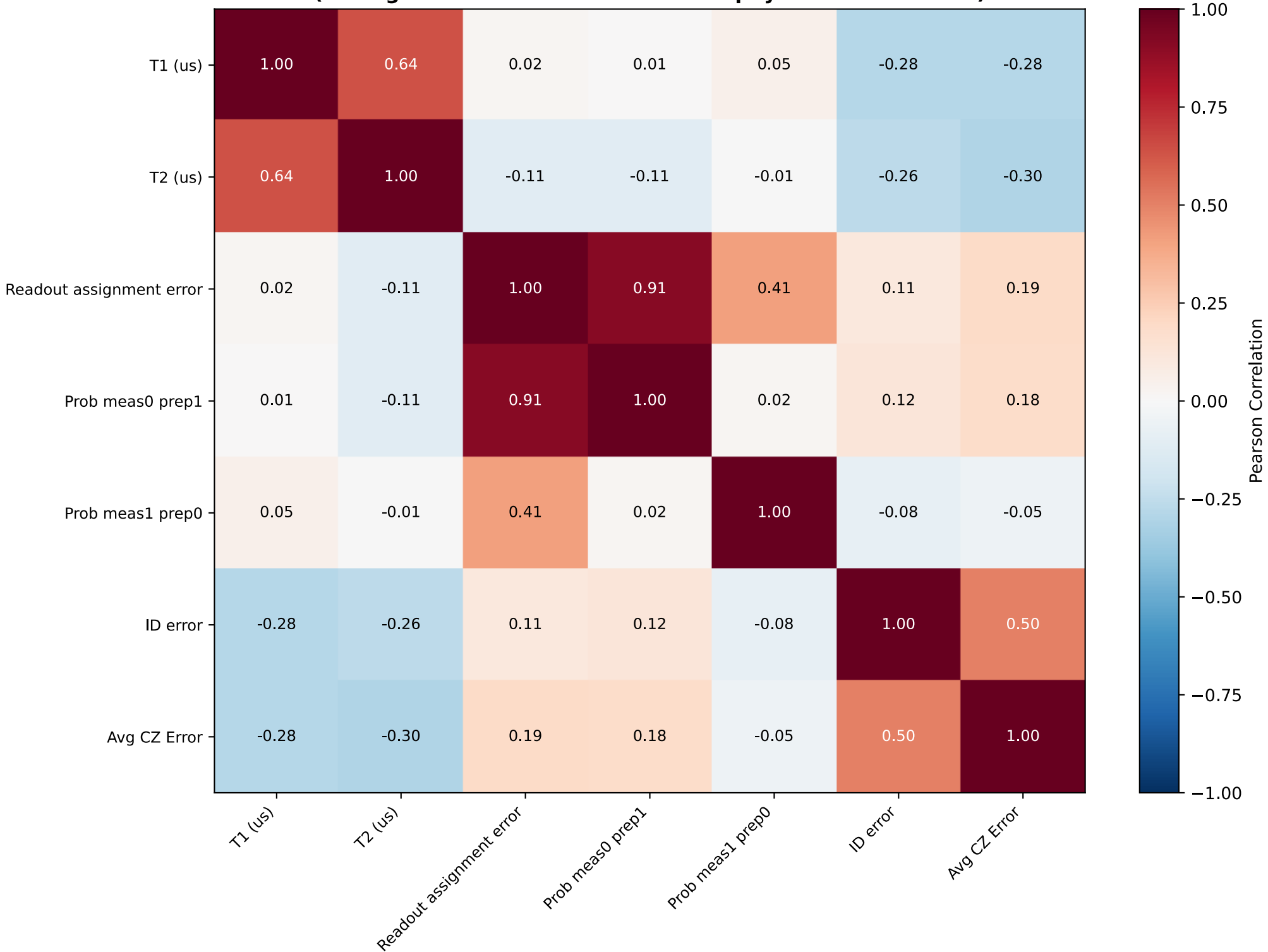
Single-Qubit Gate Error Comparison



ID Error vs T1 (expect inverse correlation)

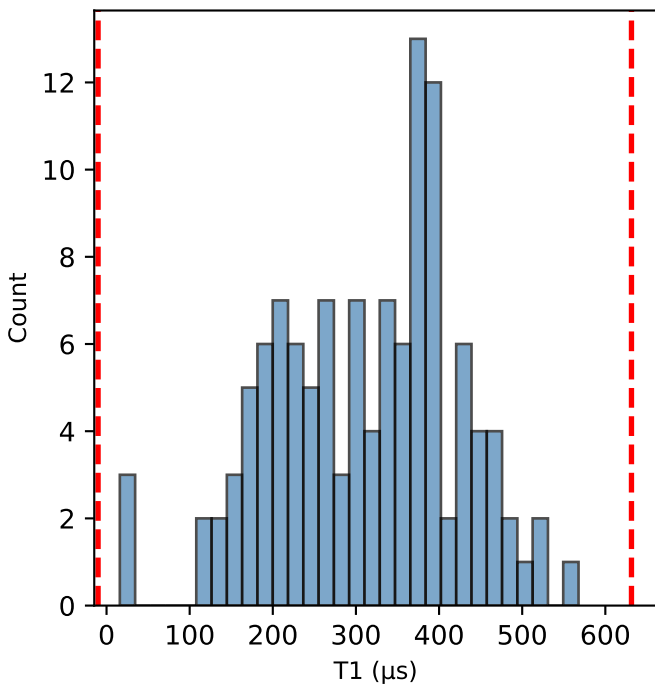


Parameter Correlation Matrix
(Strong correlations indicate shared physical mechanisms)

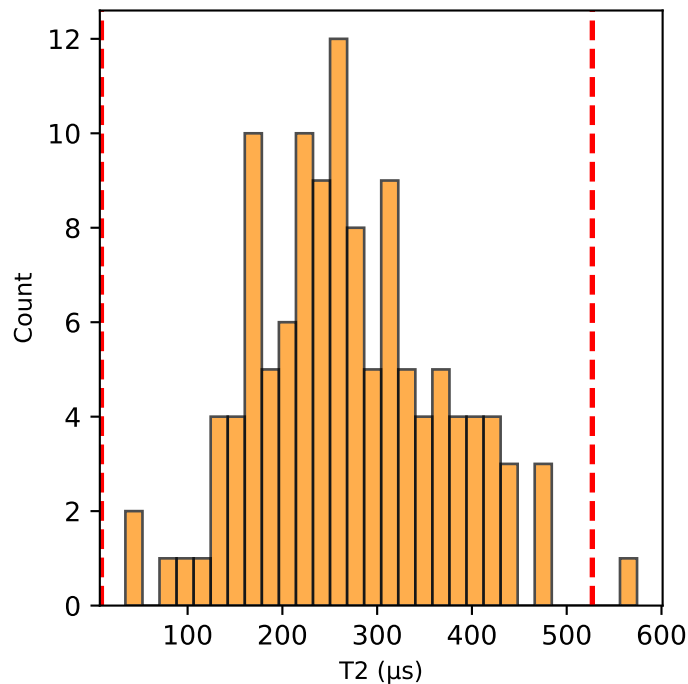


Outlier Detection Summary (IQR Method: $>Q3 + 1.5 \times IQR$)

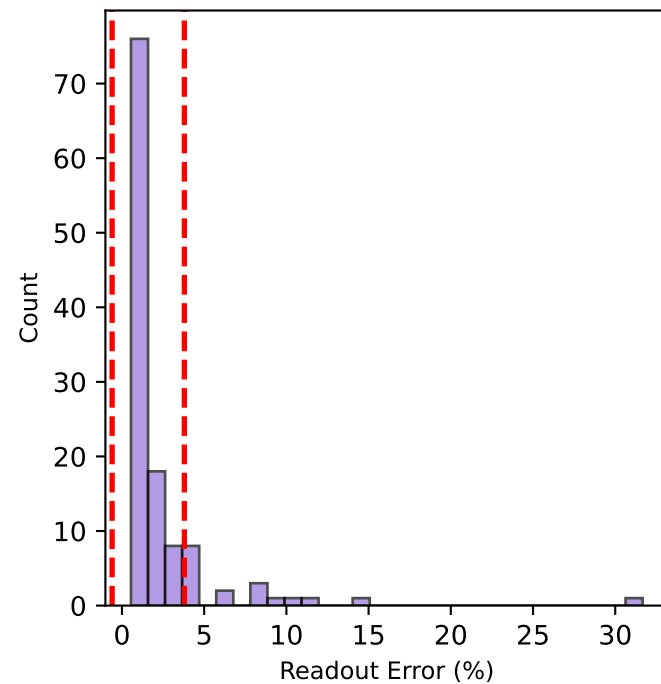
T1 (us)
0 outliers (0.0%)



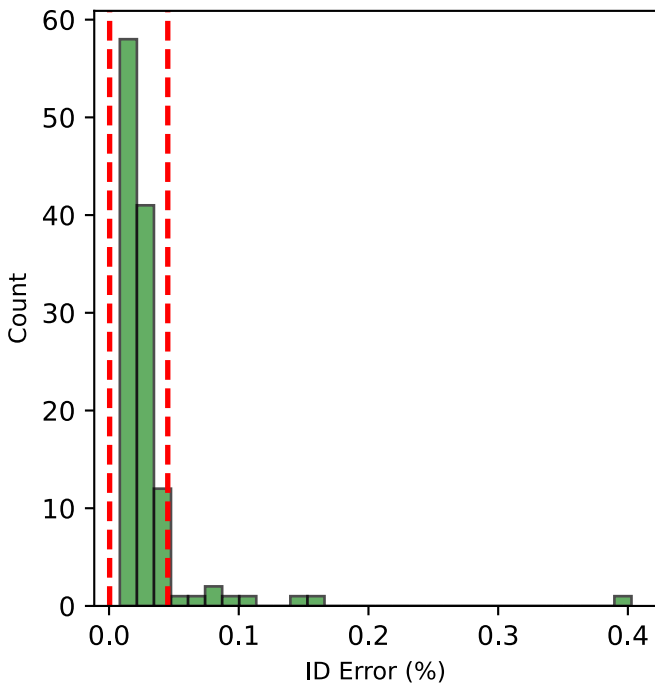
T2 (us)
1 outliers (0.8%)



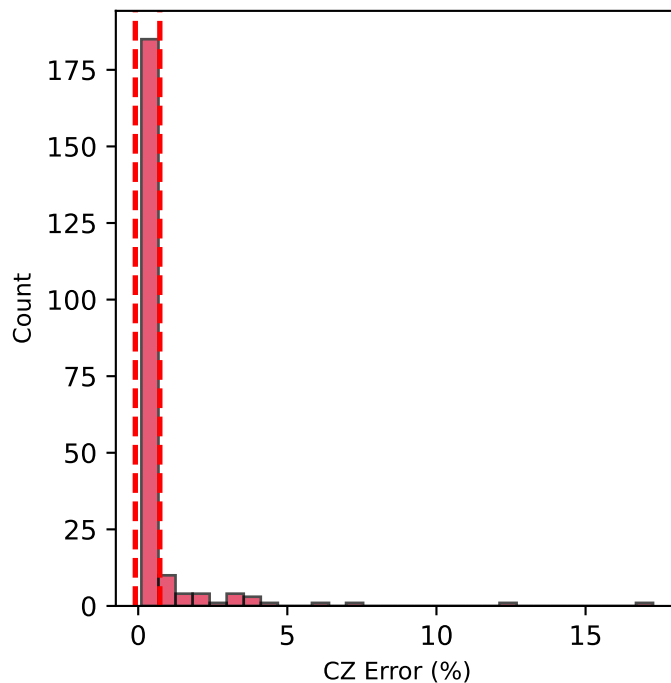
Readout
16 outliers (13.3%)



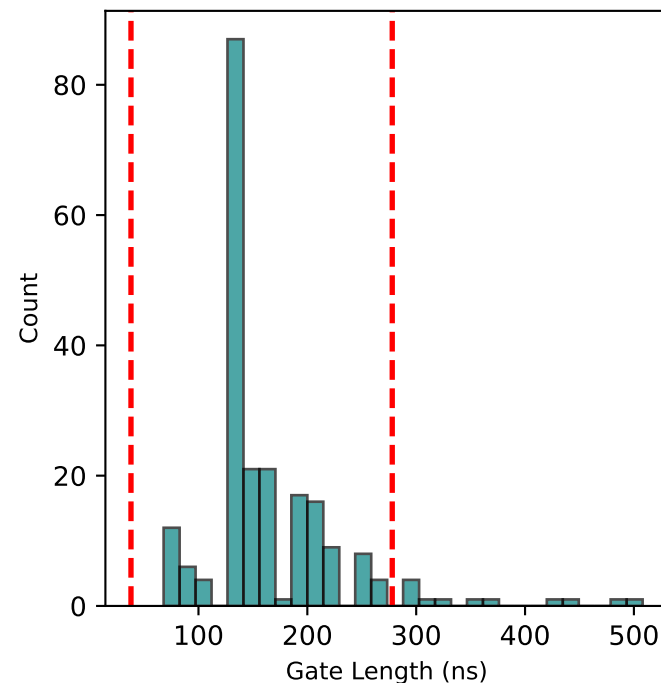
ID Error
11 outliers (9.2%)



CZ Error
29 outliers (13.4%)



Gate Length
12 outliers (5.5%)



15 WORST Qubits
(Highest composite error score)

| Qubit | T1 (μs) | T2 (μs) | Readout | ID Err | CZ Err |
|-------|---------|---------|---------|--------|--------|
| 6 | 16 | 34 | 2.39% | 0.144% | 10.21% |
| 48 | 307 | 46 | 14.44% | 0.070% | 6.32% |
| 29 | 162 | 153 | 3.82% | 0.403% | 5.01% |
| 88 | 371 | 223 | 31.67% | 0.020% | 0.41% |
| 28 | 232 | 249 | 11.76% | 0.075% | 3.71% |
| 73 | 19 | 266 | 1.95% | 0.021% | 0.28% |
| 74 | 21 | 303 | 1.39% | 0.022% | 1.29% |
| 7 | 111 | 192 | 3.52% | 0.024% | 5.94% |
| 108 | 226 | 279 | 8.20% | 0.101% | 1.14% |
| 86 | 128 | 107 | 7.85% | 0.015% | 0.95% |
| 21 | 183 | 213 | 0.98% | 0.154% | 0.36% |
| 60 | 200 | 201 | 1.18% | 0.082% | 2.30% |
| 99 | 159 | 158 | 2.71% | 0.097% | 0.41% |
| 75 | 205 | 104 | 0.95% | 0.044% | 1.18% |
| 51 | 214 | 163 | 8.44% | 0.022% | 0.23% |

15 BEST Qubits
(Lowest composite error score)

| Qubit | T1 (μs) | T2 (μs) | Readout | ID Err | CZ Err |
|-------|---------|---------|---------|--------|--------|
| 13 | 487 | 481 | 0.63% | 0.009% | 0.21% |
| 16 | 393 | 347 | 0.68% | 0.010% | 0.19% |
| 3 | 344 | 405 | 1.21% | 0.008% | 0.18% |
| 0 | 387 | 467 | 1.46% | 0.015% | 0.12% |
| 1 | 381 | 423 | 1.04% | 0.017% | 0.16% |
| 24 | 568 | 399 | 0.66% | 0.019% | 0.31% |
| 26 | 421 | 344 | 0.83% | 0.018% | 0.19% |
| 40 | 432 | 375 | 1.76% | 0.012% | 0.16% |
| 11 | 264 | 319 | 0.68% | 0.012% | 0.22% |
| 9 | 263 | 365 | 1.23% | 0.011% | 0.23% |
| 59 | 307 | 402 | 1.33% | 0.017% | 0.19% |
| 10 | 393 | 433 | 1.10% | 0.029% | 0.12% |
| 119 | 461 | 479 | 2.83% | 0.010% | 0.25% |
| 62 | 505 | 322 | 0.92% | 0.021% | 0.26% |
| 113 | 374 | 344 | 1.21% | 0.015% | 0.32% |

Comprehensive Statistical Summary
(Outliers detected via IQR method)

| Parameter | Count | Mean | Std | Median | Min | Max | Outliers |
|-------------------|-------|----------|----------|----------|---------|----------|----------|
| T1 (μs) | 120 | 312.2645 | 111.1582 | 327.3846 | 15.9922 | 567.7464 | 0 |
| T2 (μs) | 120 | 271.1514 | 97.6975 | 264.6408 | 34.3711 | 574.2115 | 1 |
| Readout Error (%) | 120 | 2.4098 | 3.5237 | 1.2878 | 0.5493 | 31.6650 | 16 |
| P(0 1) (%) | 120 | 3.2762 | 7.9575 | 1.7212 | 0.6348 | 81.1523 | 15 |
| P(1 0) (%) | 120 | 1.6774 | 2.7148 | 0.9033 | 0.1709 | 19.7754 | 16 |
| ID Error (%) | 120 | 0.0304 | 0.0406 | 0.0221 | 0.0083 | 0.4028 | 11 |
| CZ Error (%) | 216 | 0.7003 | 1.6642 | 0.2917 | 0.1075 | 17.2622 | 29 |
| Gate Length (ns) | 218 | 163.9266 | 68.1380 | 138.0000 | 68.0000 | 508.0000 | 12 |